Foreword

Welcome to the 25th Asian Test Symposium (ATS’16) in its silver jubilee year. Since 1992, ATS has been held every year in various Asian cities as the largest symposium that focuses on testing of integrated circuits and systems. Many researchers and engineers from all over the world have attended the past symposia and enjoyed discussions. We hold this silver jubilee symposium to bring back its birthplace Hiroshima City.

We have received 98 technical paper submissions from 13 countries and regions, including 48 from Asian countries and regions except Japan, 18 from Europe, 15 from North America and 17 from Japan. Each paper was sent to at least three reviewers for evaluation. The Program Committee meeting was held on July 22, 2016, at Hiroshima City University, and 46 papers were selected based on the reviewers’ rating and comments. The selected papers, which cover nearly all aspects of the key area of VLSI testing, were allocated into 15 technical sessions. We have also received eight industry paper submissions and all of them are accepted to form an industry session.

In addition to the technical and industry sessions, the ATS program includes two plenary sessions, two special sessions, one session for the doctoral thesis contest, one poster session, one special panel session and two half-day tutorials. An opening keynote address and two invited talks in the plenary sessions will be given by Mr. John M. Carulli Jr, Dr. Yervant Zorian and Mr. Michael Chen, respectively. We will honor to the late Prof. Edward J. McCluskey with a special keynote delivered by Prof. Cheng-Wen Wu and tributes from several prominent speakers in the first plenary session. One of the special session is organized by Prof. Mehdi Tahoori and Prof. Krishnendu Chakrabarty and the other is organized by Prof. Sandip Kundu. The special panel session is entitled "Past, present and future of ATS" and will be held in commemoration of the 25th ATS anniversary. Two half-day tutorials are offered in cooperation with the Test Technology Test Education Program (TTEP) of IEEE Computer Society, Test Technology Technical Council (TTTC). One is on yield analysis by Dr. Yu Huang, Dr. Wu Yang and Dr. Wu-Tung Cheng and the other is on system level testing by Dr. Artur Jutman, Prof. Hans-Joachim Wunderlich and Prof. Matteo Sonza Reorda.

Finally, we would like to thank the reviewers, the Program Committee members, the Organizing Committee members, 25th Anniversary Program Committee members, and the ATS Steering Committee members for their cooperation. We also thank to all the authors who submitted their works to this 25th Asian Test Symposium, and the program participants for their contribution at the symposium. So, let us enjoy this 25th Asian Test Symposium in its silver jubilee year.

Tomoo Inoue, Hiroshima City University
General Co-Chair

Satoshi Ohtake, Oita University
Program Chair

Hiroshi Takahashi, Ehime University
General Co-Chair

Hideyuki Ichihara, Hiroshima City University
Program Vice-Chair

Yukiya Miura, Tokyo Metropolitan University
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